
THERMAL ISSUES IN ELECTRONICS APPLICATIONS

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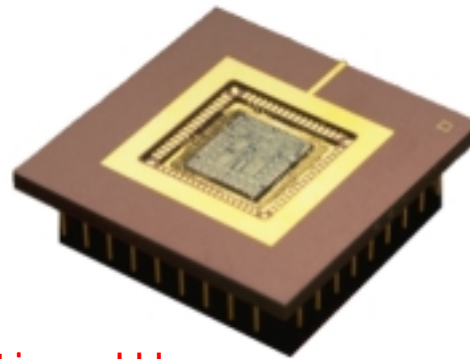
Microelectronics Heat Transfer Laboratory

40 Watts! What's the big deal?



Light Bulb

- Power: 40 W
- Area: 120 cm²
- Flux: 0.33 W/cm²



Pentium III

- * 0.25 micron CMOS technology
- * 9.5 million transistors
- * 450 - 550 MHz

Silicon

- Power: 40 W
- Area: 1.5 cm²
- Flux: 26.7 W/cm²

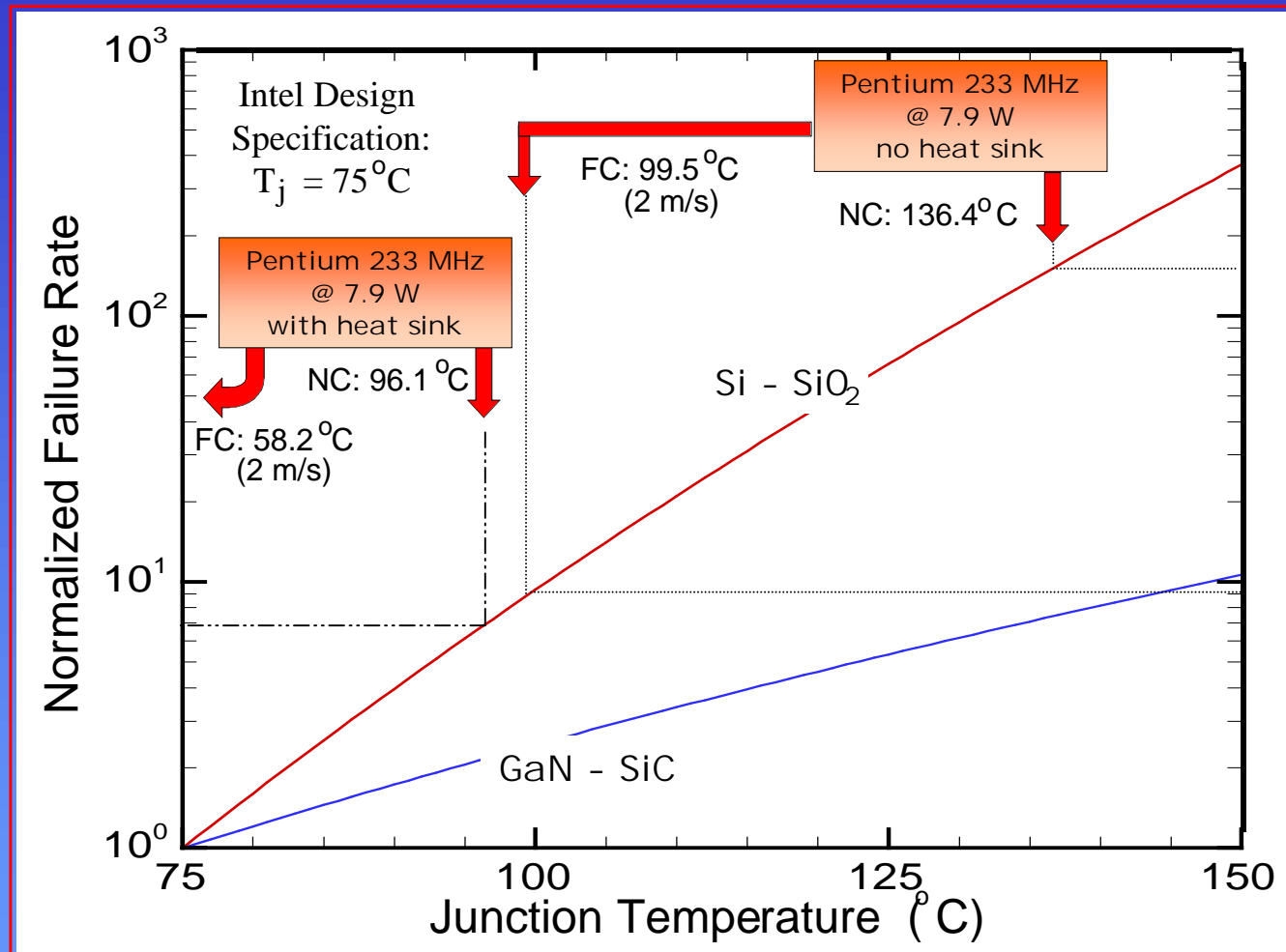
Package

- R_{j-c}: 0.94 C/W
- R_{j-a}: 6.8 C/W (no heat sink)
- R_{j-a}: 2.5 C/W (heat sink)

80 x

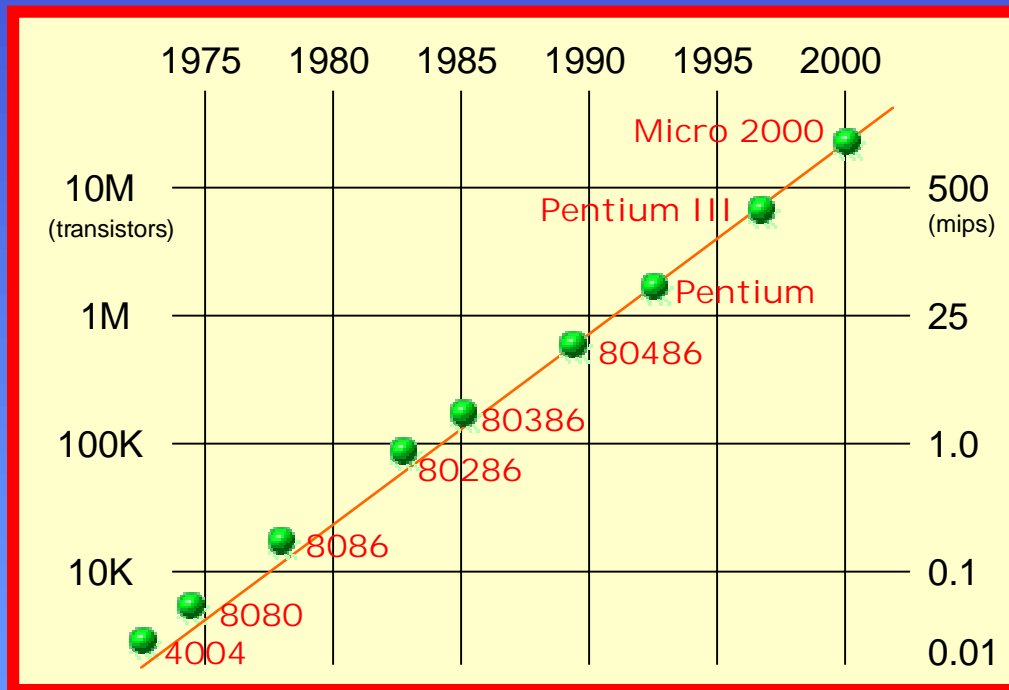


Component Failure Rate



Moore's Law (1965)

- each new chip contains roughly twice as much capacity as its predecessor
- a new generation of chips is released every 18 - 24 months



From: www.intel.com

- in 26 years, the population of transistors per chip has increased by 3,200 times



IC Trends: Past, Present & Future

	1980	1999	2003	2006	2012
Comp. Per Chip	0.2 M	6.2 M	18 M	39 M	100 M
Frequency (MHz)	5	1250	1500	3500	10000
Chip Area (sq. cm)	0.4	4.45	5.60	7.90	15.80
Max. Power (W)	5	90	130	160	175
Junction Temp. (C)	125	125	125	125	125

From: David L. Blackburn, NIST



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What Does The Future Hold?

- More of the same?
 - higher packaging densities
 - higher heat fluxes
- Can we rely on a technology break through?
 - ie. Bipolar \Leftrightarrow CMOS \Leftrightarrow ?
- Thermal design tools must become part of a fully integrated design tool set

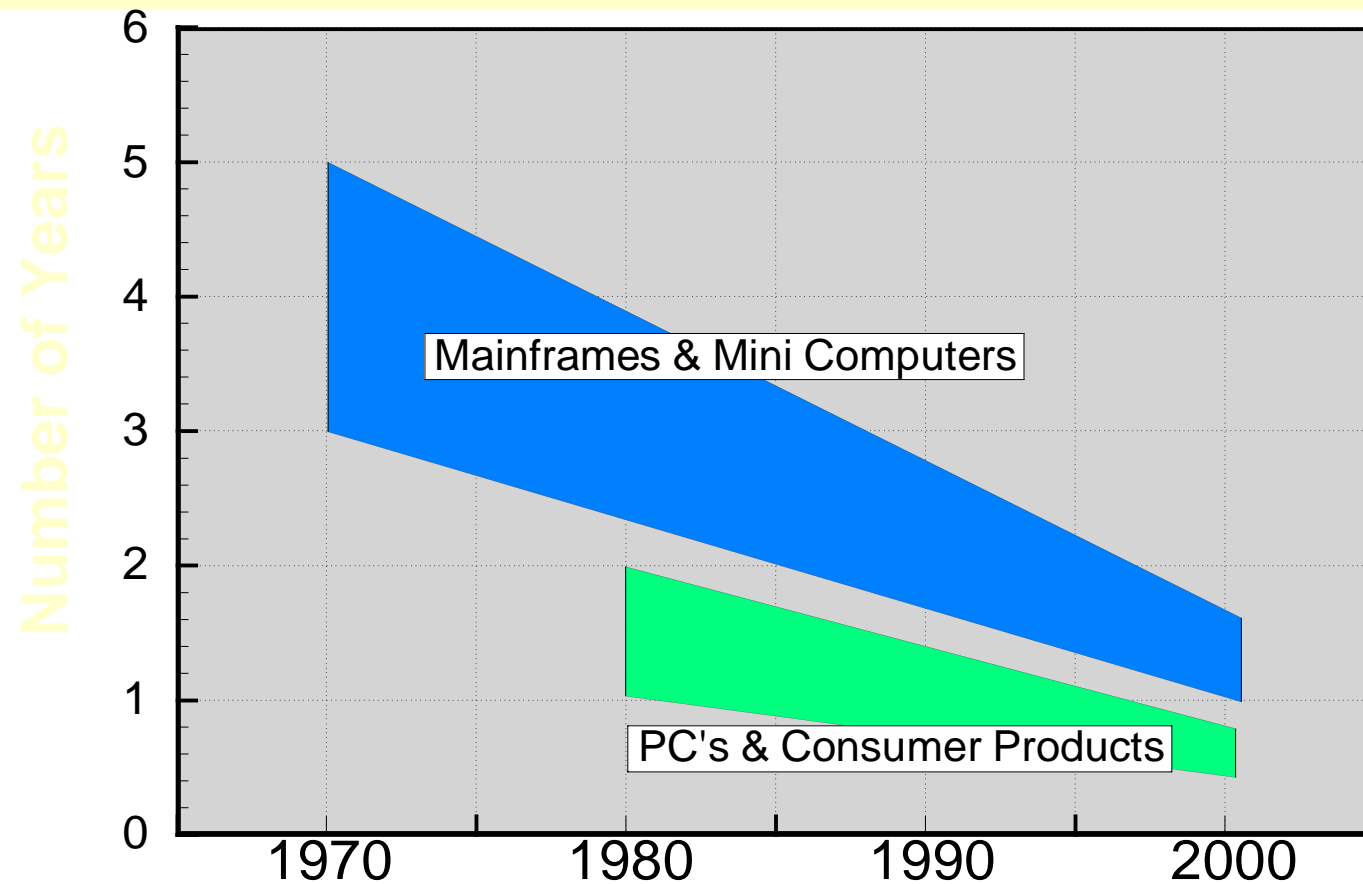


Design Challenges

- Reduce design cycle times to a minimum
 - numerical simulation and prototype testing are becoming less viable
 - especially during preliminary design cycles
 - optimization tools
- Concurrent design
 - requires multidisciplinary skills
 - simplicity is imperative



Product Design Cycle



Future Considerations

- Optimization tools
 - faster models
 - I/O portability for concurrent designs
- Improved access to design tools
 - web tools
 - extranets
 - machine portability
 - standardized test methods

